



Tests of Ultra Fast Silicon Detectors

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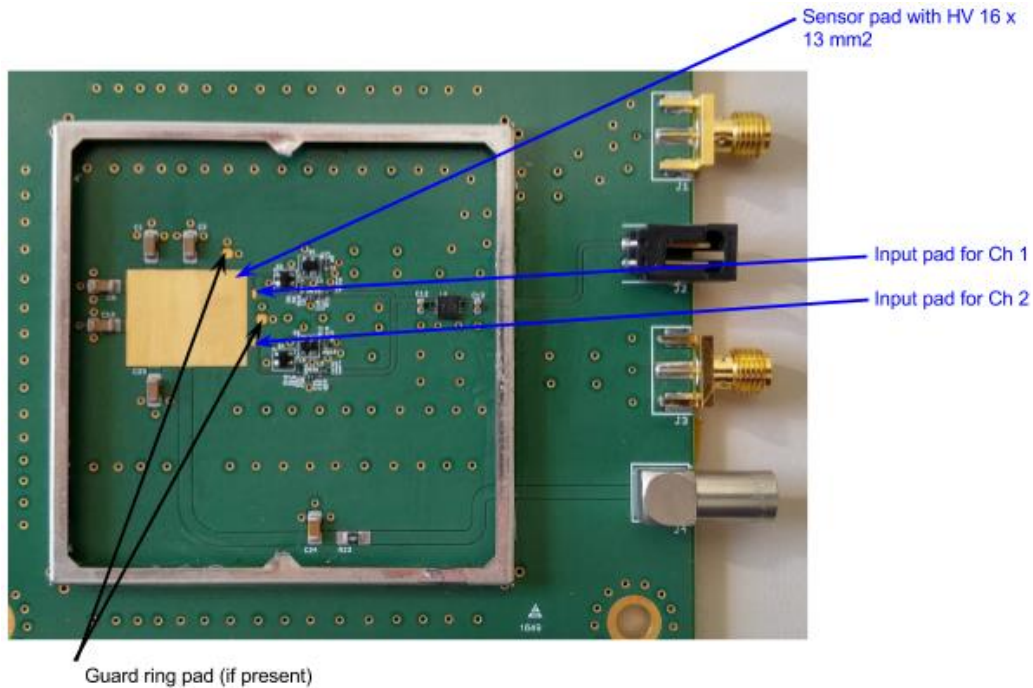
R. Arcidiacono, N. Cartiglia, M. Ferrero, V. Sola
C. Royon, H. Al Ghouf, P. Pare

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KU

Multi purpose board for a silicon/diamond detector



A two channels board that can be use for the characterization of different solid state detectors.

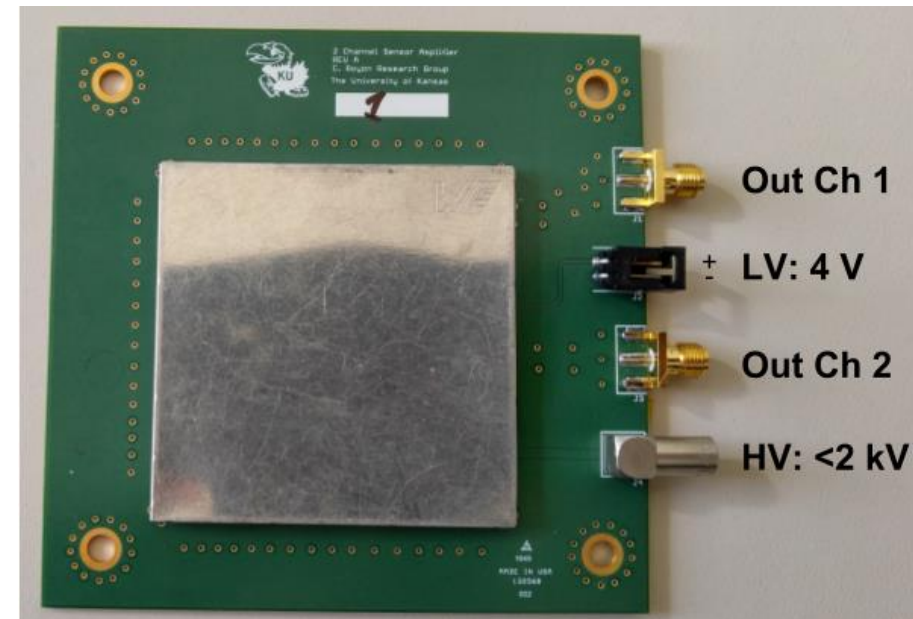


< 200 USD per board
(10 produced)

Sensors up to 16x13 mm² can be glued and bonded.

The components can be easily adapted to accommodate:

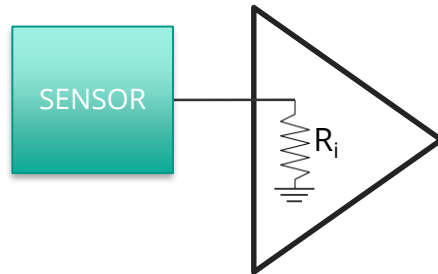
- Diamond sensors: ~1 nA bias current, both polarities, small signal
- Silicon detectors: ~100 nA bias current, small signal
- UFSi: ~100 nA bias current, ~ larger signal
- SiPM: ~ 5 uA bias current, large signal



Amplifier with high input impedance

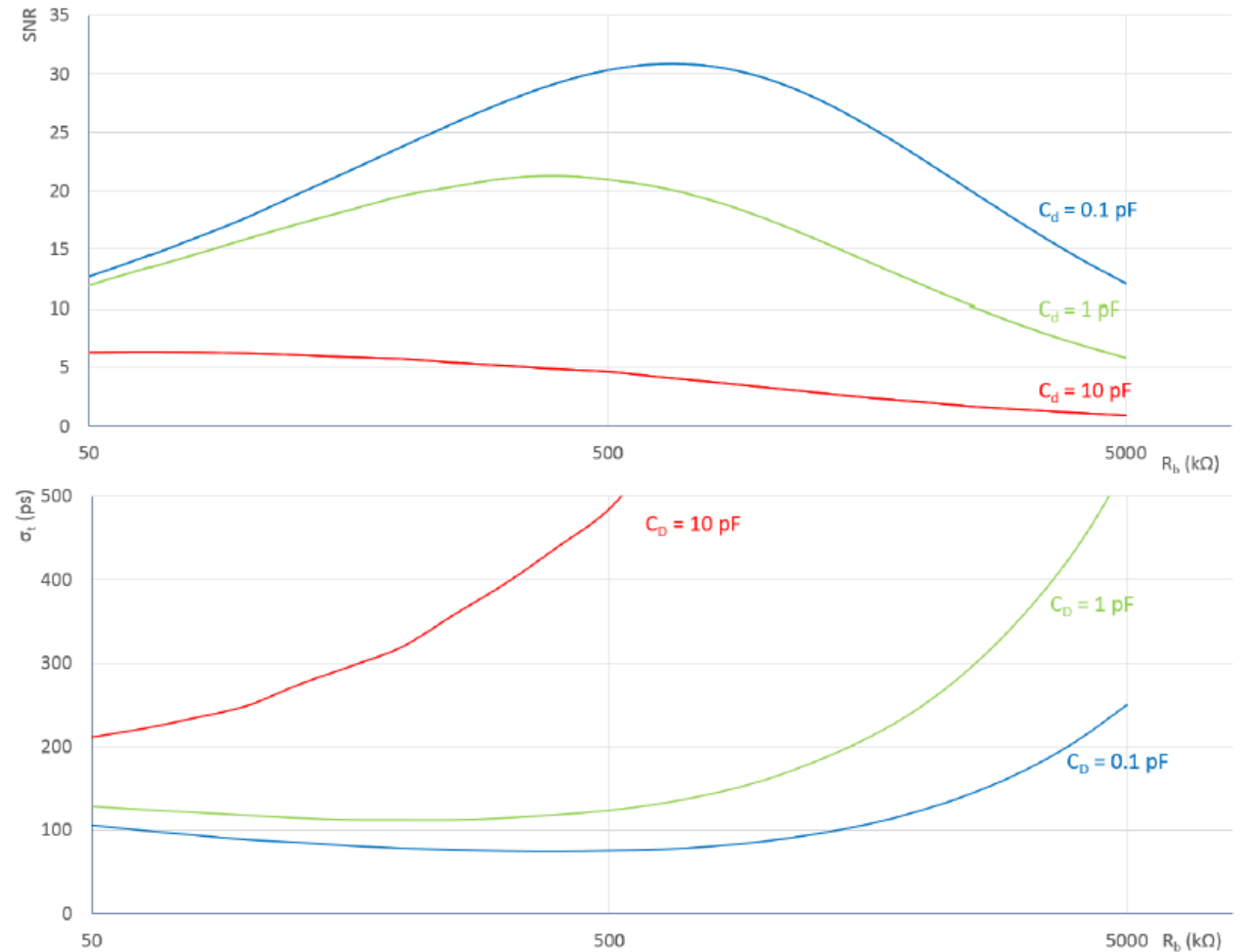


An amplifier with High Input impedance has some advantage of a Broadband Amplifier ($50\ \Omega$) and some of the Charge Sensitive Amplifier



The input impedance has to be selected according to the characteristics of the sensor.

The main advantage/disadvantage is that there are no general purpose commercial solutions!

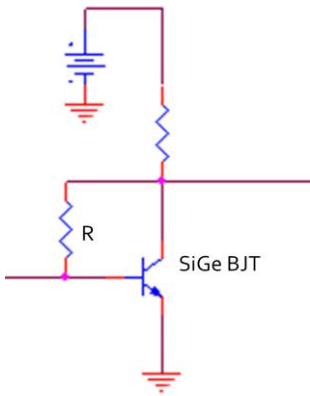


Simulated SNR and time resolution for a diamond detector.

Amplifier with high input impedance

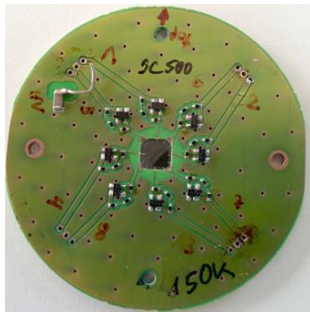


One implementation of a HImp amplifier is using a common emitter with a feedback resistor

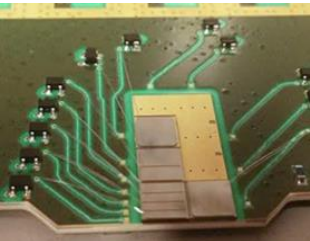


The best value of R for timing has to be optimized according to the sensor:

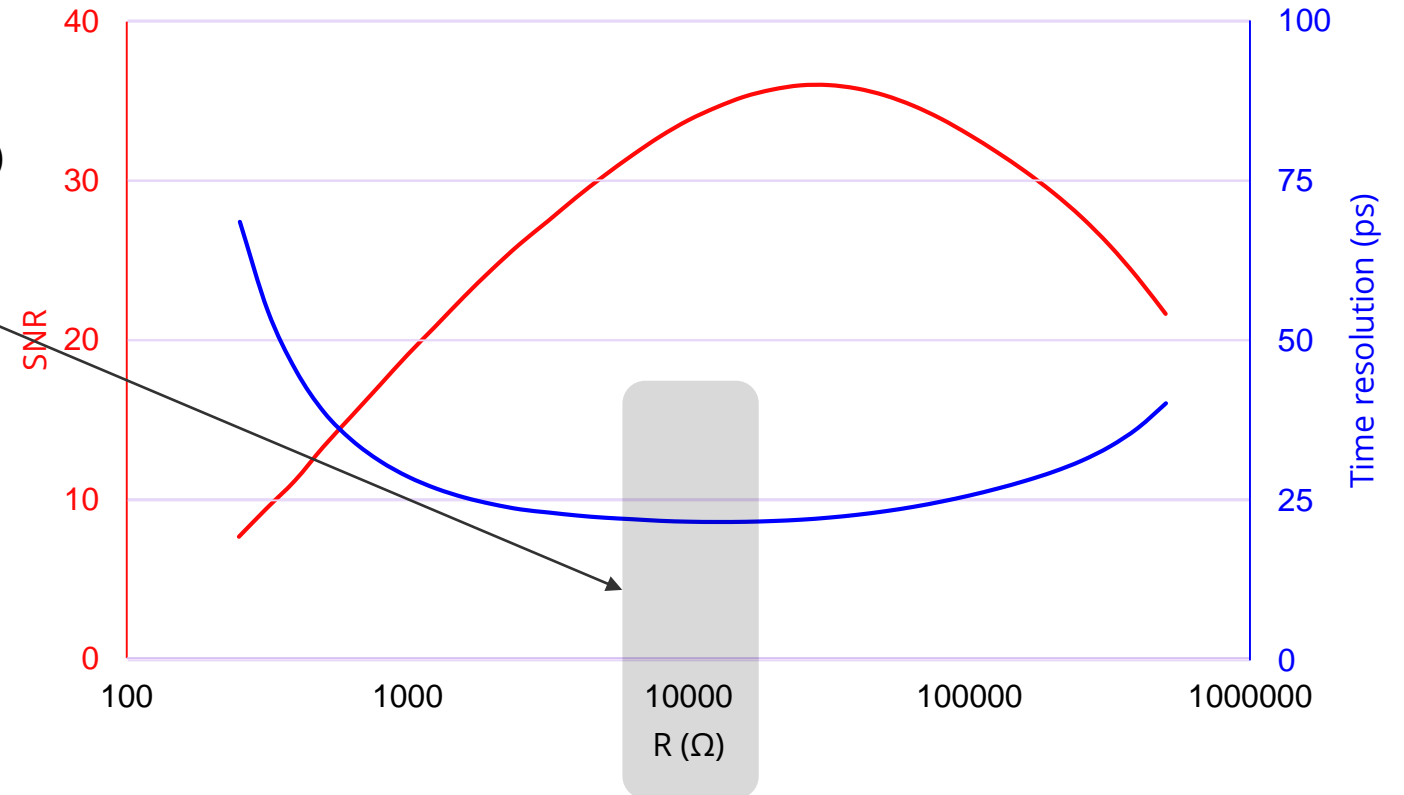
- High for diamonds ($R \sim 300 \text{ k}\Omega$)
- Lower for thick UfSD ($R \sim 30 \text{ k}\Omega$)
- Low for $50 \mu\text{m}$ UfSD



HADES @ GSI
[10.1016/j.nima.2010.02.113](https://doi.org/10.1016/j.nima.2010.02.113)



TOTEM @ CERN
See talks tomorrow



Optimization for UfSD



The signal generated at the passage of a MIP by a 50 μm UfSD can be simulated using Weightfield2*

Using Weightfield2 it is possible to simulate different detectors, in different configurations.

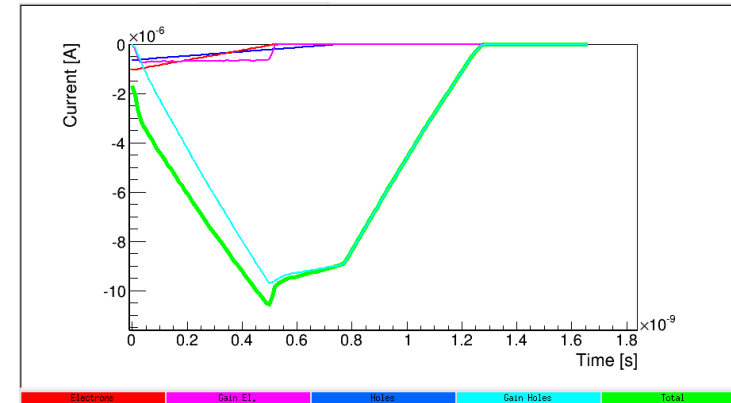
The reliability of the simulations have been proved in several occasions.

[arXiv:1608.08681](https://arxiv.org/abs/1608.08681)

[Timing capabilities of Ultra-Fast Silicon Detector](#)

A simplified signal can be used to simulate the behavior of several types of amplifiers.

50 μm UfSD at 200V with a gain 15



*: <http://personalpages.to.infn.it/~cartigli/Weightfield2/Main.html>

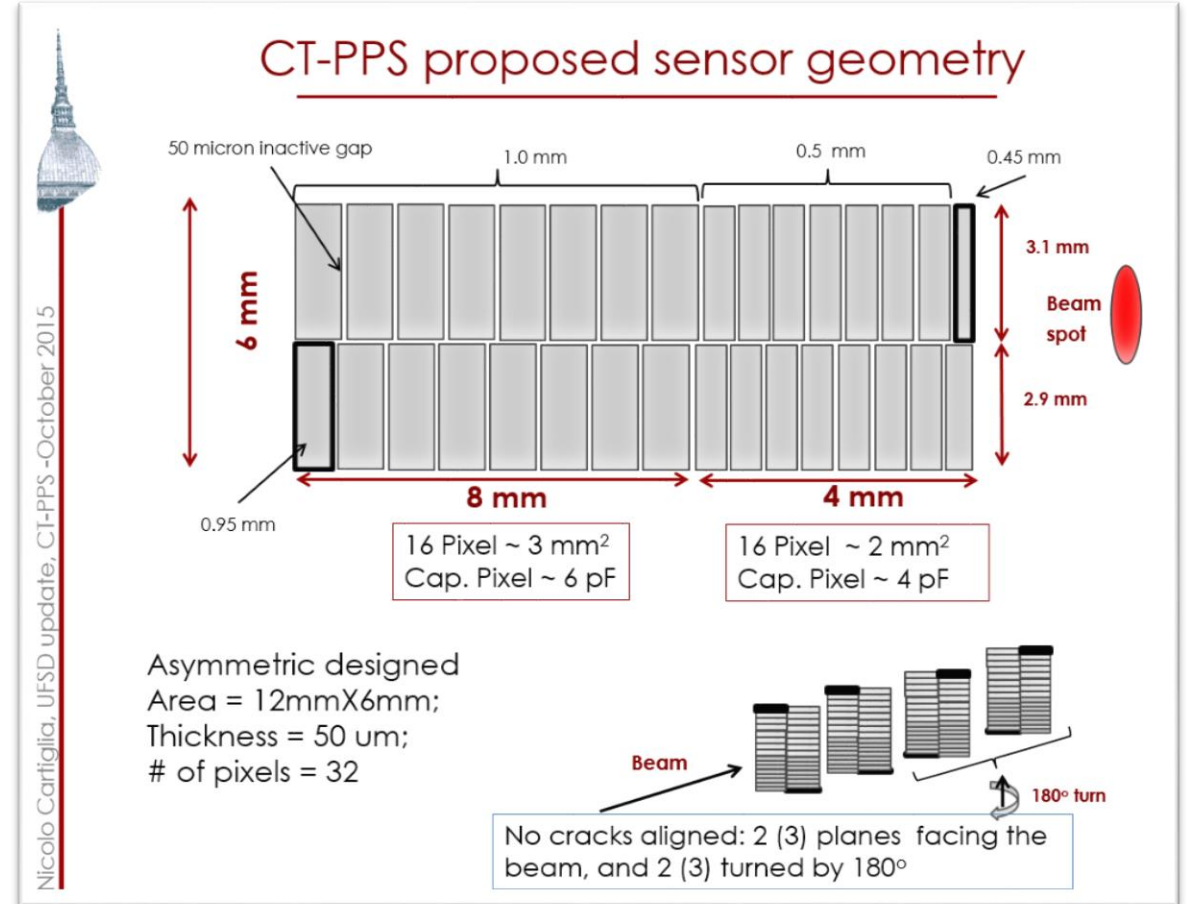
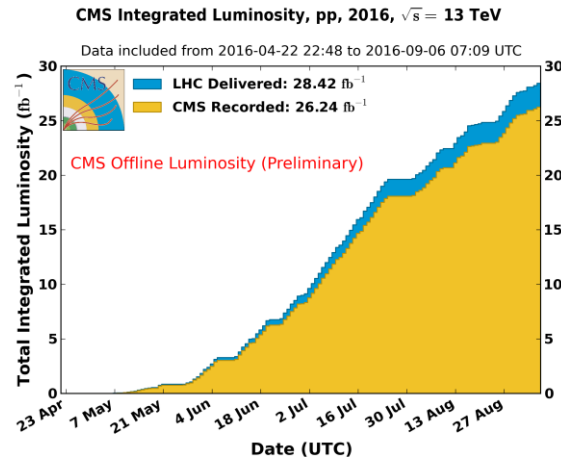
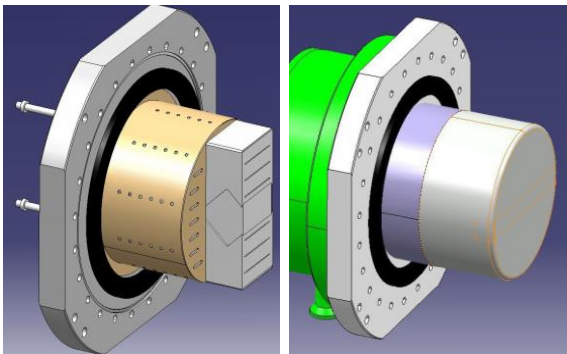
The timing detector for CT-PPS



CMS TOTEM Proton Precision Spectrometer (CT-PPS) adds precision proton tracking and timing detectors in the very forward region on both sides of CMS to study central exclusive production (CEP) in proton-proton collisions.

Requirement of the timing detector:

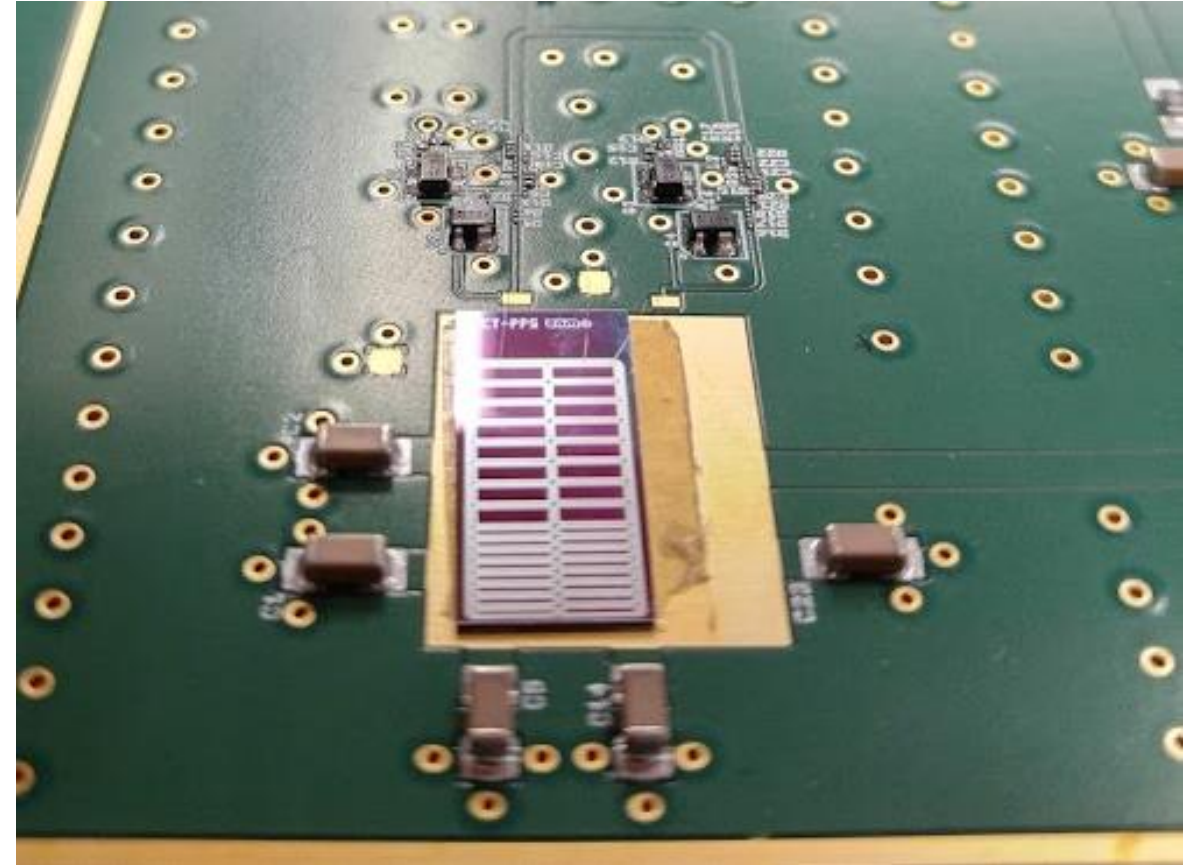
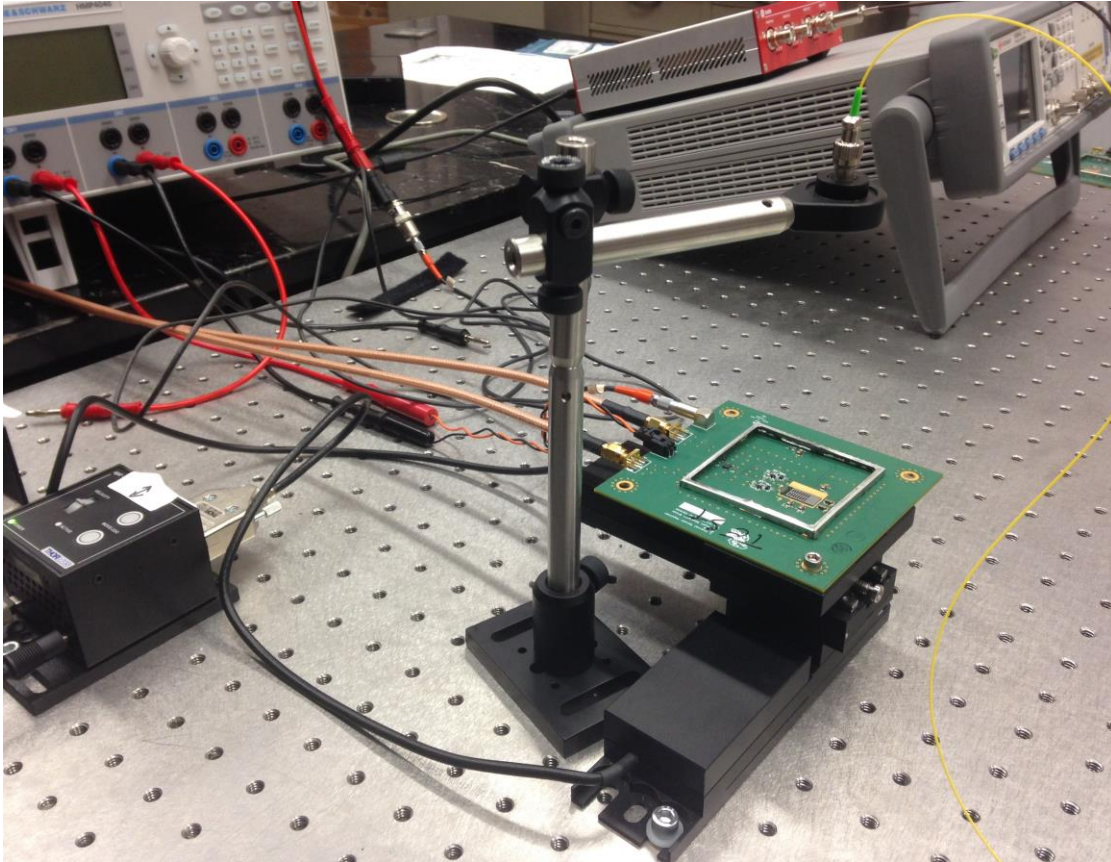
- Small active area ($\sim 4 \text{ cm}^2$)
- Small dead region at the edge and between channels
- Low power consumption and low material budget
- Radiation hard (proton flux of $5 \times 10^{15} \text{ cm}^{-2}$ per 100 fb^{-1})
- Time resolution of 10-30 ps.



Test of the amplifier in KU



The amplifier was first test using a laser pulse to measure the behaviour with sensors of different capacitance

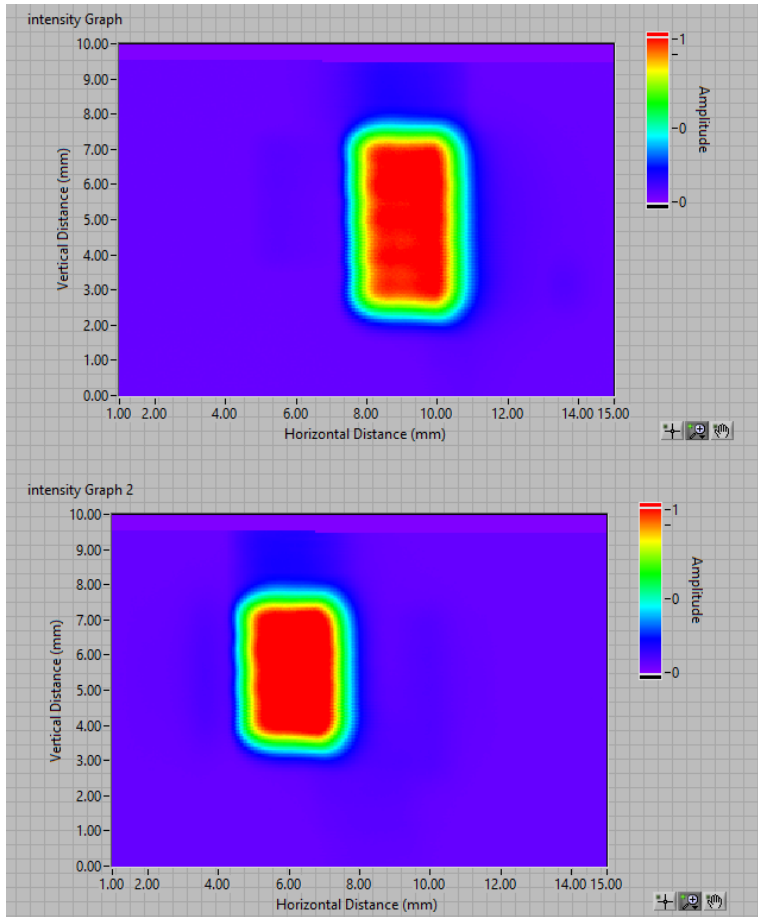


1080 nm picosecond laser, 50 ps wide pulses with peak power > 100 mW set at 10 cm away from the sensor board
The support can be moved XY with micrometric accuracy

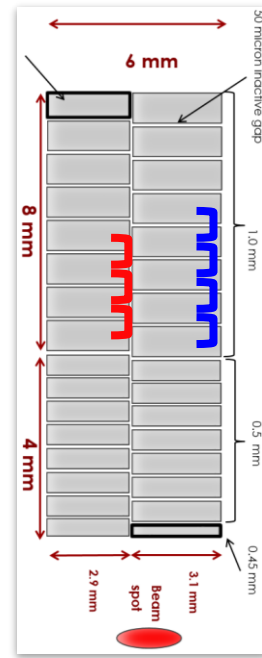
Test of the amplifier in KU



The amplifier was first test using a laser pulse to measure the behaviour with sensors of different capacitance



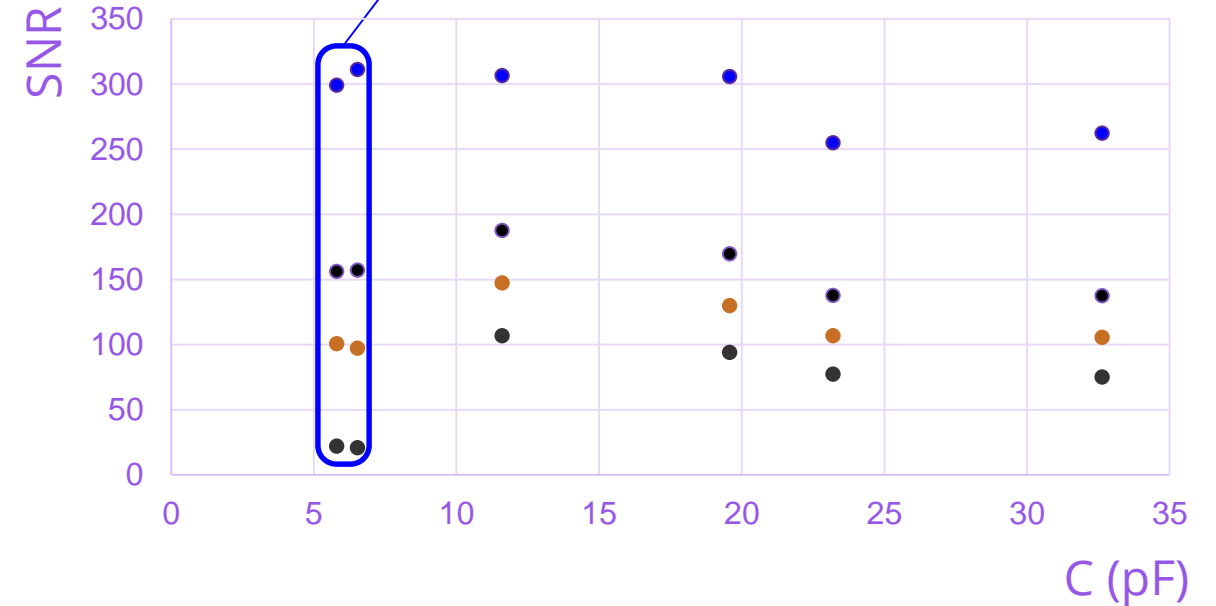
$3.1 \times 5 \text{ mm}^2 \sim 33 \text{ pF}$



$2.9 \times 4 \text{ mm}^2 \sim 24 \text{ pF}$



Laser spot larger than the pad:
partial light collection



● Laser Tune at 50%
● Laser Tune at 80%

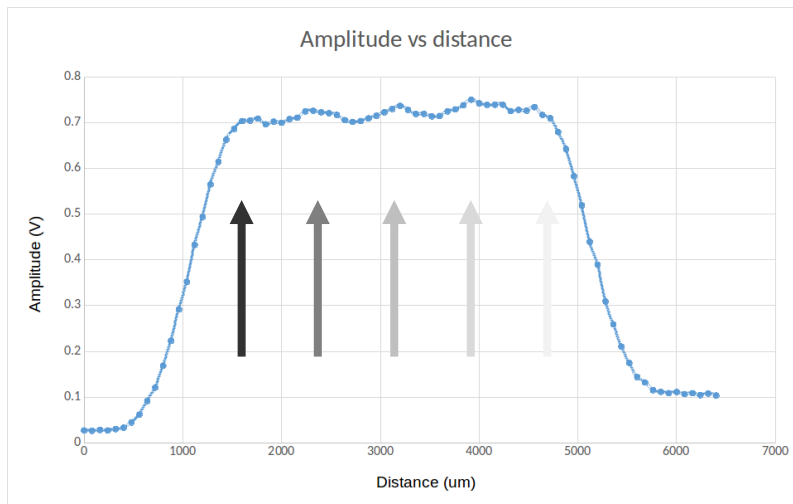
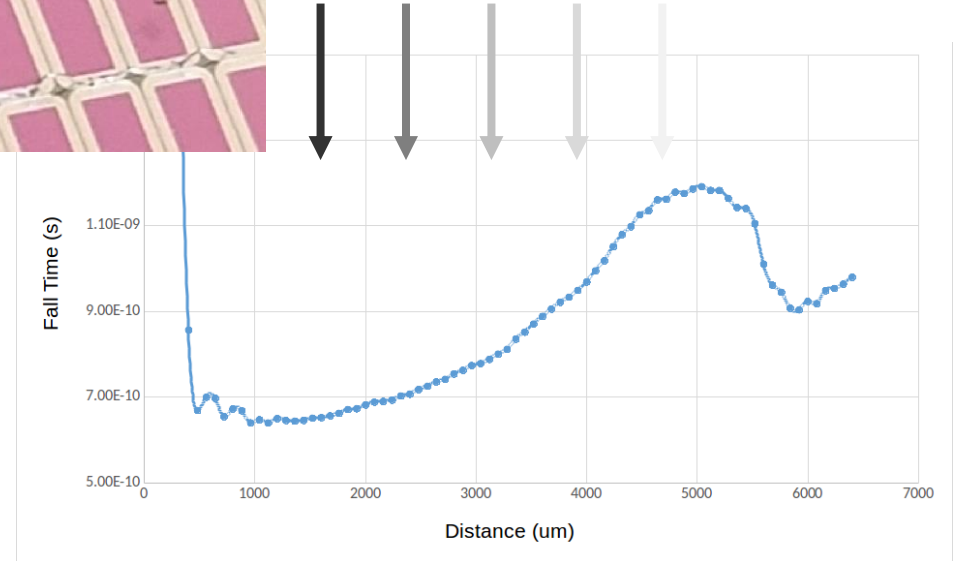
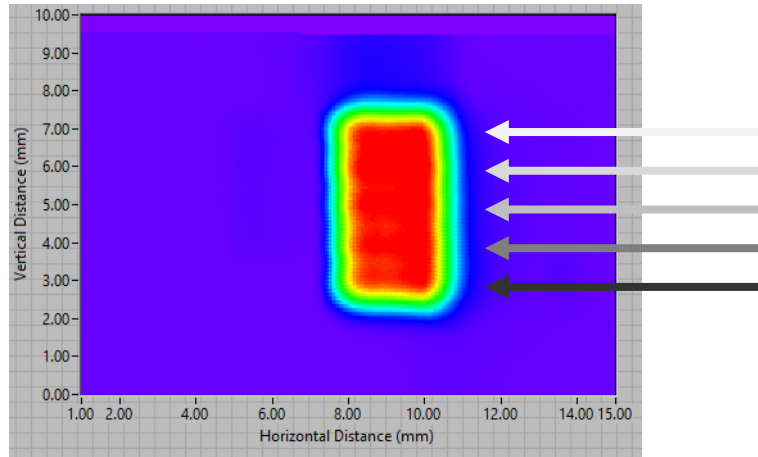
● Laser Tune at 75%
● Laser Tune at 85%

To test the amplifier with sensors of increasing capacitance, more than one pad were connected to the same amplifier

Test of the amplifier in KU



The amplifier was first test using a laser pulse to measure the behaviour with sensors of different capacitance



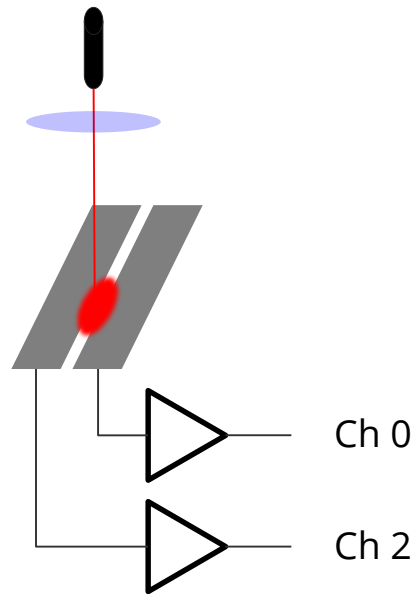
However, the fall-time shows a strong dependency

The amplitude of the signal has a weak dependence on the position of the laser spot

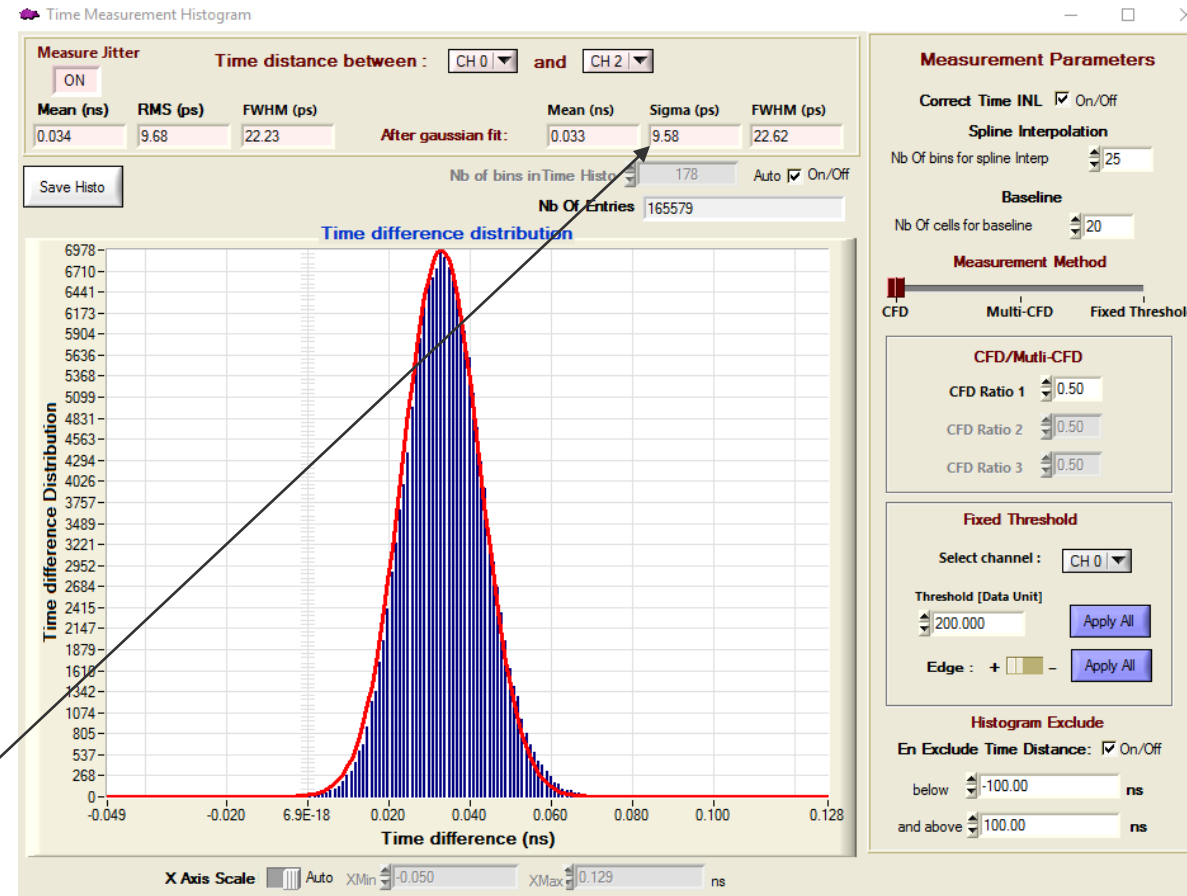
Test of the amplifier in KU



The amplifier was first test using a laser pulse to measure the behaviour with sensors of different capacitance



$\sigma \sim 10\text{ps}$

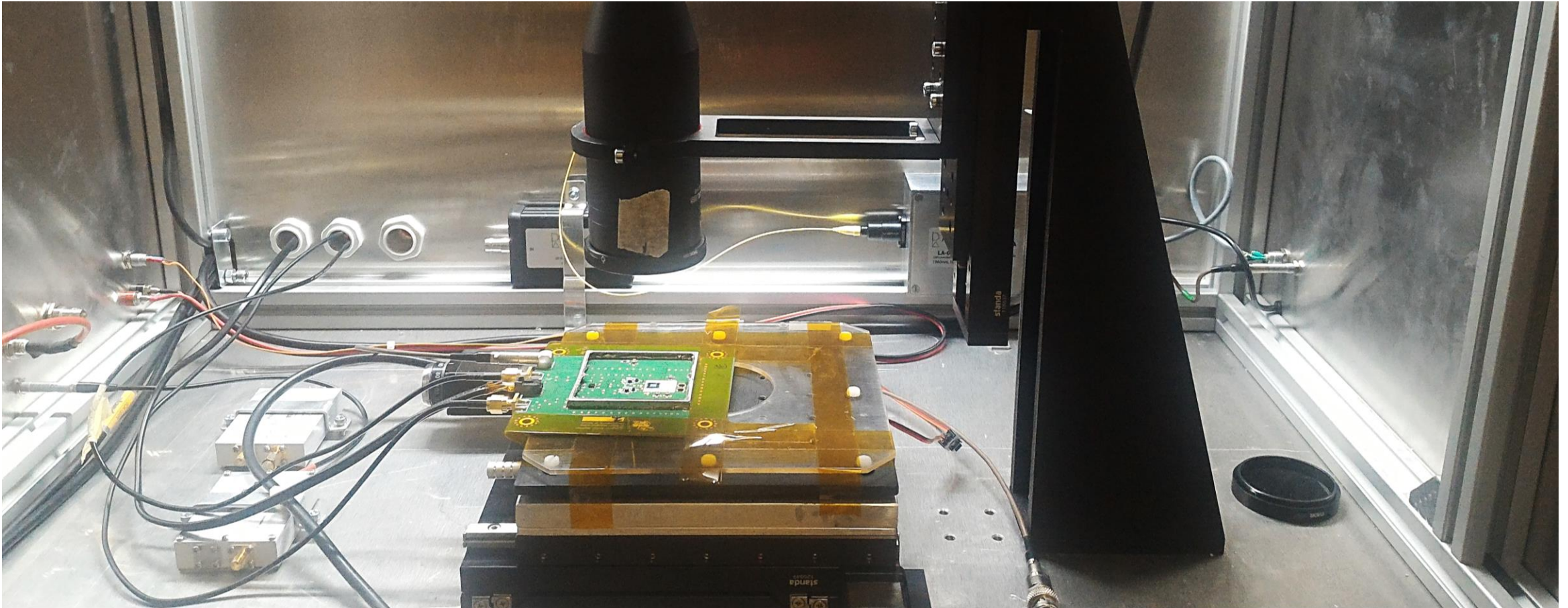


Time difference between two neighboring pixels with the laser, measured using the SAMPIC evaluation board

Test of the amplifier in Turin



The amplifier was first test using a laser pulse, calibrated using cosmic rays and a radioactive source (Sr^{90})

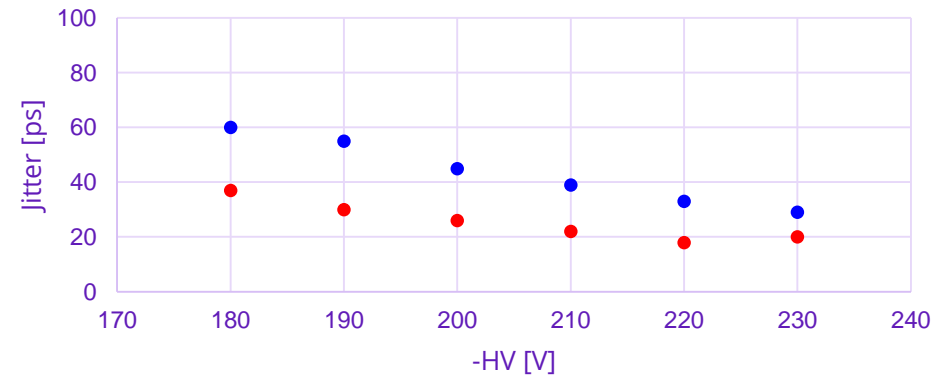
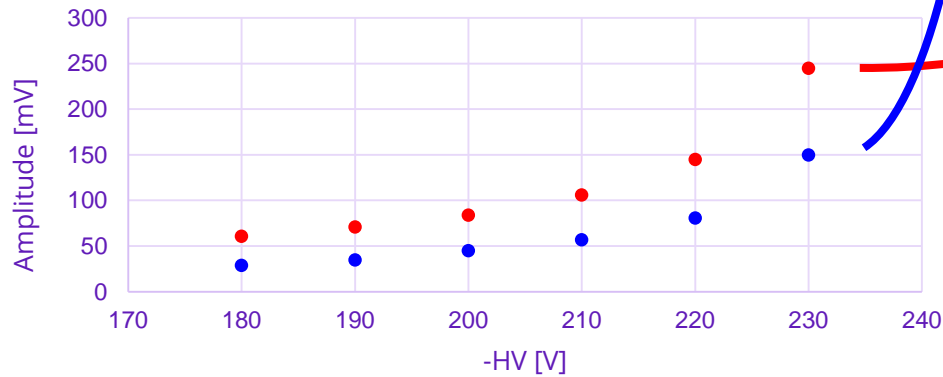
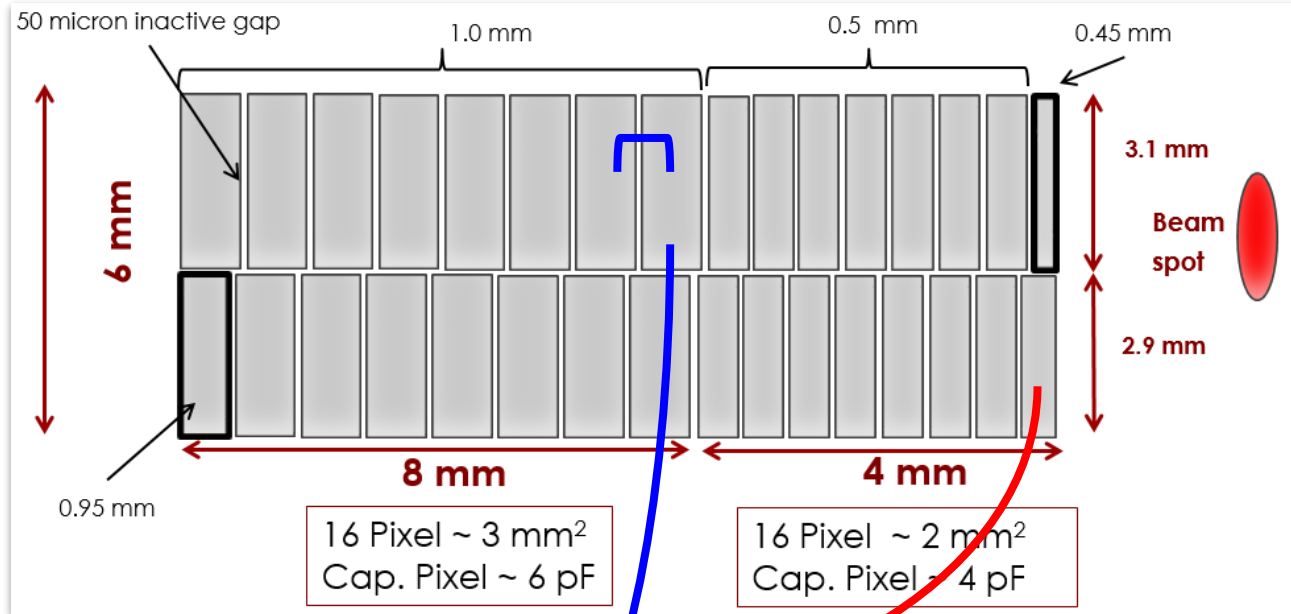


The laser pulse was focused on $\sim 50 \mu\text{m}$ spot; the power was calibrated using a Sr^{90} and

UFSD for CT-PPS



The CT-PPS sensor was used to test the amplifier with a pad of ~ 3 pF and one of ~ 12 pF



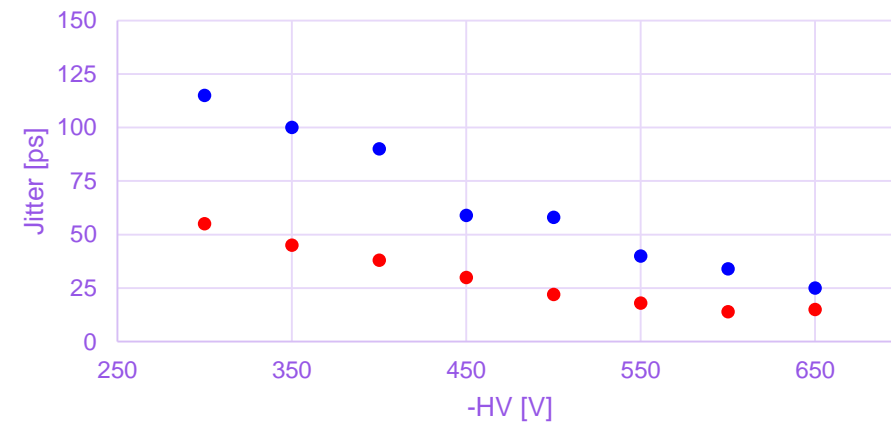
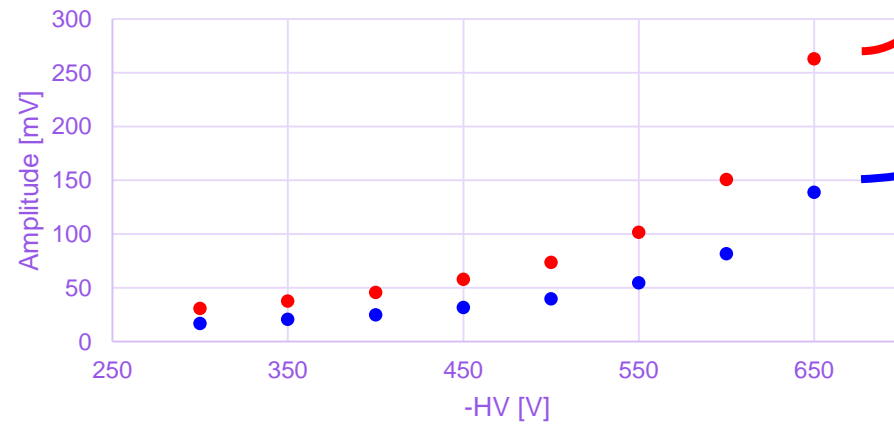
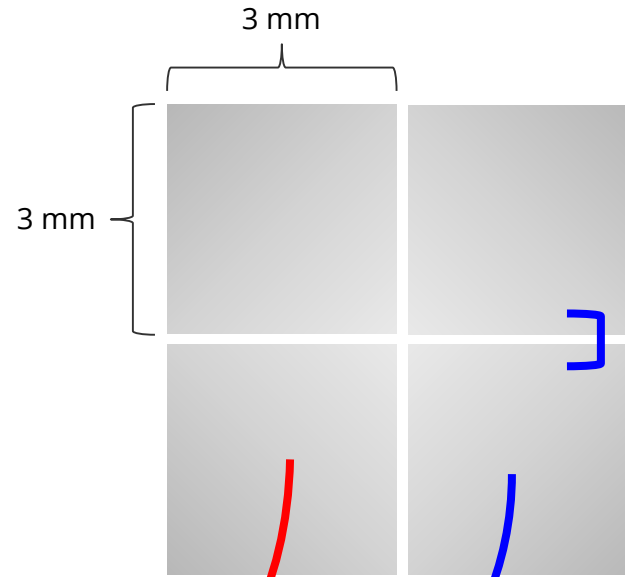
● 0.5x2.9 mm² pad ● 2x 1x3.1 mm² pads

● 0.5x2.9 mm² pad ● 2x 1x3.1 mm² pads

UFSD produced by Hamamatsu



Hamamatsu produced some 50 μm thick LGADs, a sample with gain ~ 10 at 600V was tested





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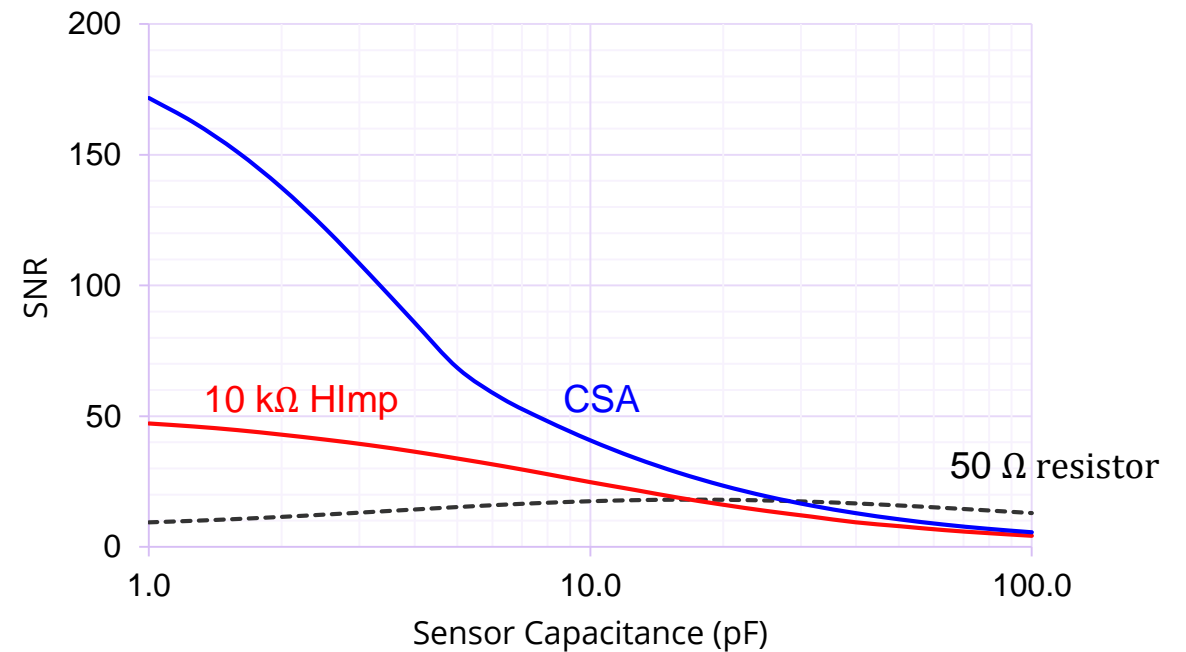
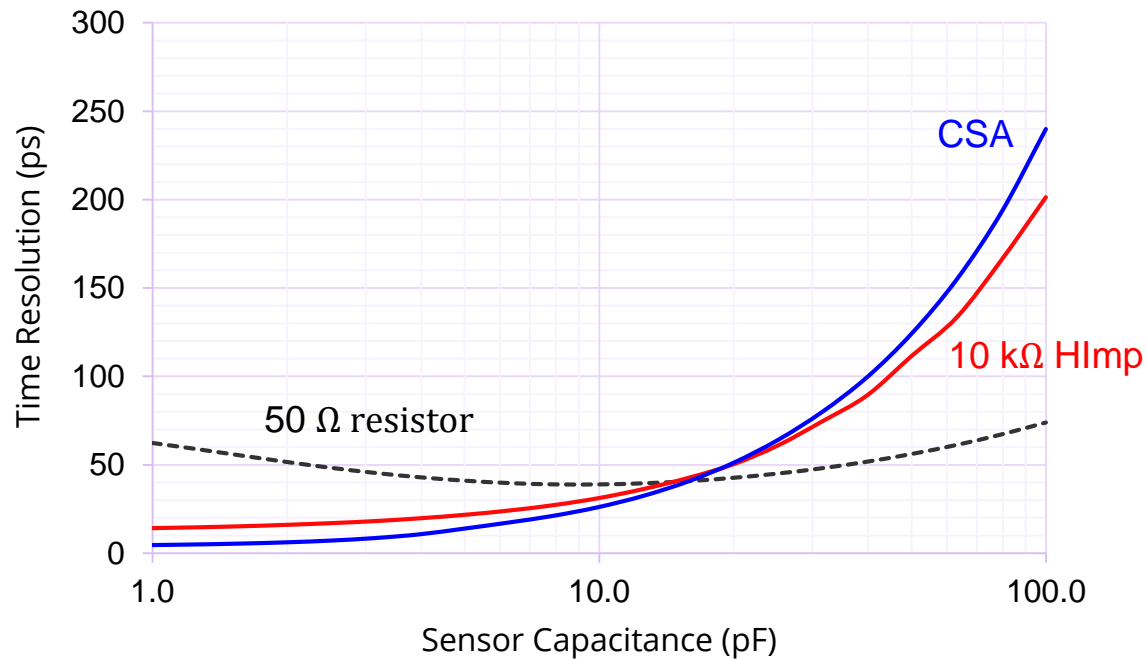
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Performance with different sensor capacitances



The behaviour of the different approaches using 50 μm UfSD can be simulated for several values of the sensor capacitance.

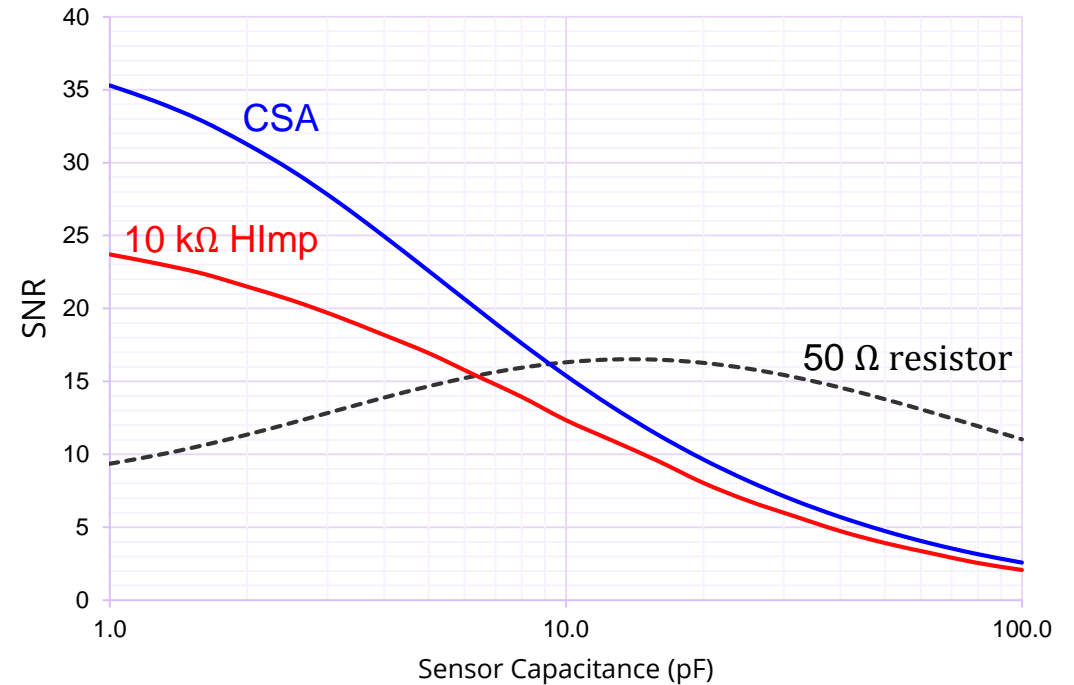
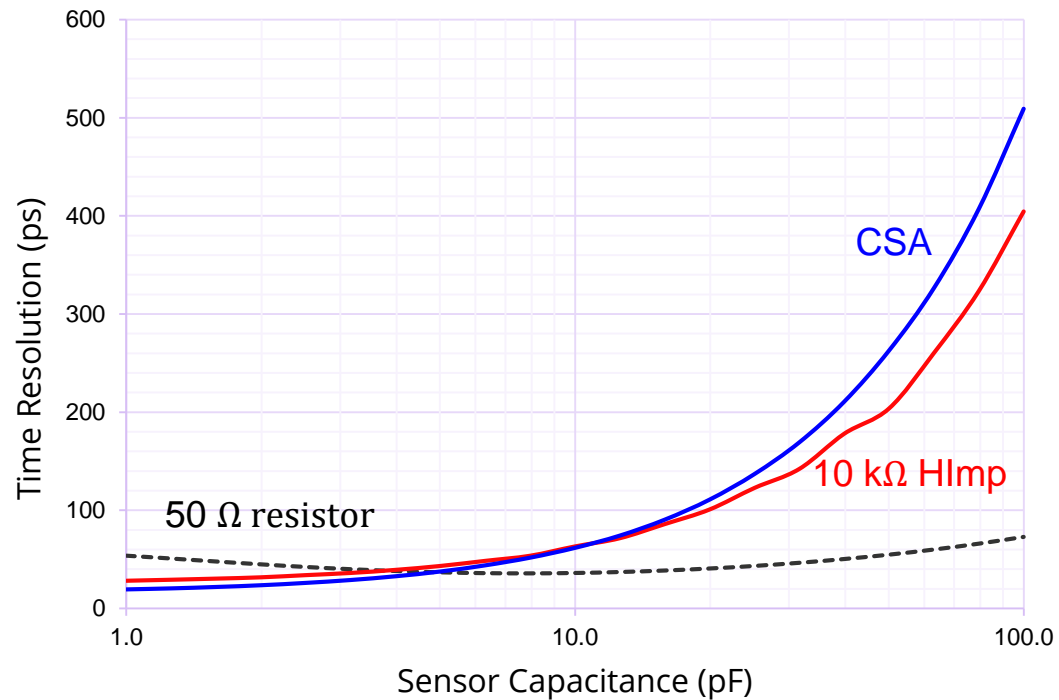


Below 15 pF the CSA is the amplifier with the best time resolution

Performance with damaged sensors



Supposing that the gain become 50% lower because of radiation damage, the CSA is still the best approach.



Below 10 pF the CSA is the amplifier with the best time resolution.

Front-end electronics: amplifier



It is useful to analyse the simplest possible case: a diamond detector read using a simple resistor.

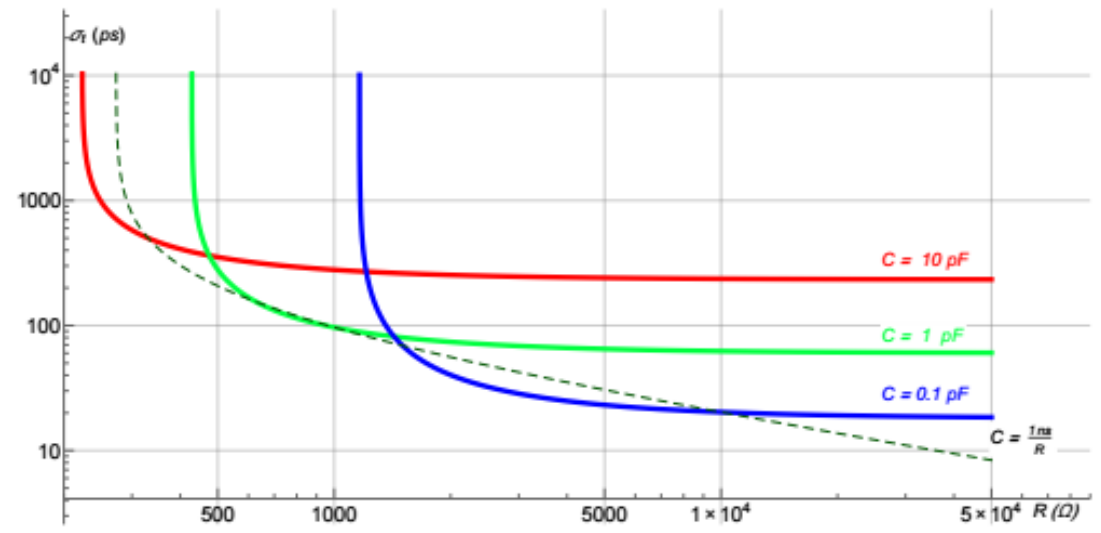
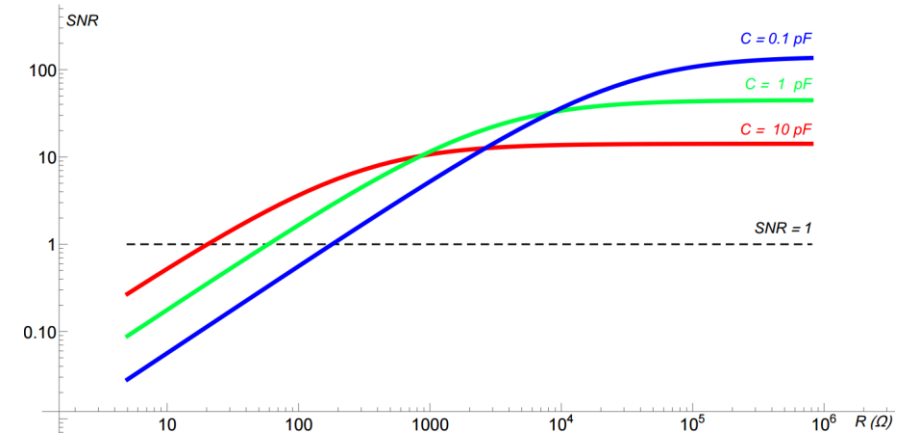
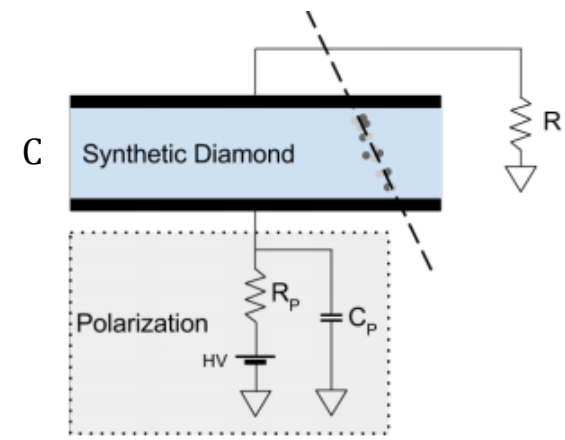
For $R < \sim 100 \Omega$ the signal is not separated from the noise ($SNR \sim 1$) also for $C \sim 0.1 \text{ pF}$.

The only way to have a $SNR > 1$ is to increase the value of the read-out resistor.

However, the time resolution is given by:

$$\sigma_t \sim \frac{\sigma_V}{\text{MAX}[\frac{dV}{dt}]}$$

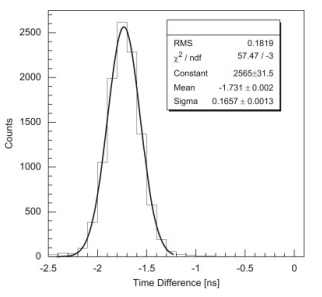
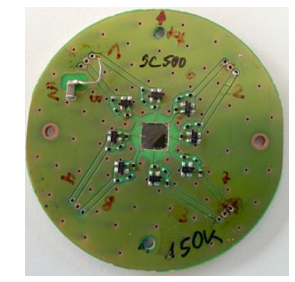
And higher R means slower signal:



A useful rule of thumb: **minimize C and use $R \sim 1 \text{ ns}/C$**

Amplifier as close as possible to the sensor (minimize C)
First stage with input resistor $\sim \text{k}\Omega$

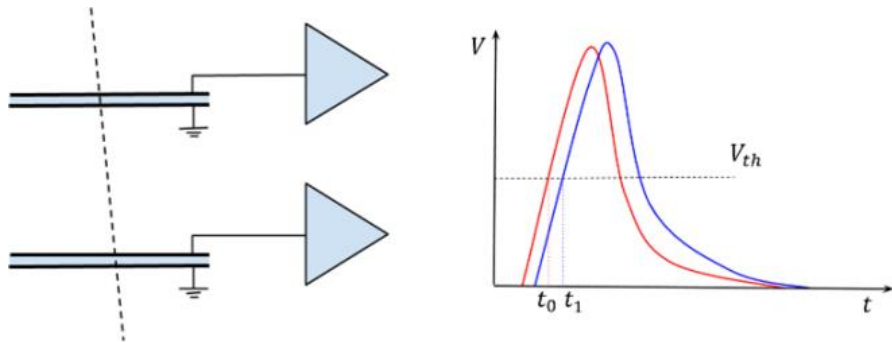
Strategy suggested by HADES @ GSI
[10.1016/j.nima.2010.02.113](https://doi.org/10.1016/j.nima.2010.02.113)



The TOTEM timing detector: timing performance



To measure the time resolution of two identical detectors it is possible to measure the arrival time of a particle crossing both sensors.

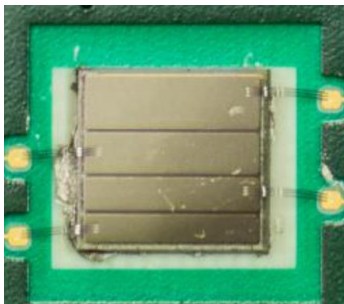


The measured time difference will be distributed around the true value because of the limited resolution of the detectors:

$$\sigma_{TOT}^2 \sim \sigma_{det1}^2 + \sigma_{det2}^2 \sim 2\sigma_{det1}^2 \longrightarrow \sigma_{meas} \sim \sqrt{2}\sigma_{det}$$

However, the time resolution depends on the capacitance of the detector!

A series of tests were done using a sensor with pads of different surface, i.e. capacitance.



Time difference between a sensor of 17.6 mm² (~1.7 pF) and sensors of different size

